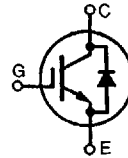


Preliminary data

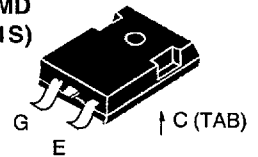
# HiPerFAST™ IGBT with Diode Combi Pack

**IXGH24N50BU1**  
**IXGH24N60BU1**

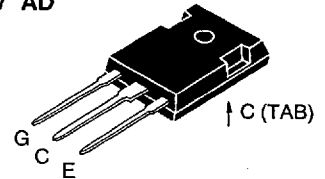
$V_{CES}$	$I_{C(25)}$	$V_{CE(sat)}$	$t_{fi}$
500 V	48 A	2.3 V	80 ns
600 V	48 A	2.5 V	80 ns



TO-247 SMD  
(24N\*\*BU1S)



TO-247 AD



G = Gate, C = Collector,  
E = Emitter, TAB = Collector

Symbol	Test Conditions	Maximum Ratings		
		24N50	24N60	
$V_{CES}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	500	600	V
$V_{CGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GE} = 1\ \text{M}\Omega$	500	600	V
$V_{GES}$	Continuous		$\pm 20$	V
$V_{GEM}$	Transient		$\pm 30$	V
$I_{C25}$	$T_C = 25^\circ\text{C}$		48	A
$I_{C90}$	$T_C = 90^\circ\text{C}$		24	A
$I_{CM}$	$T_C = 25^\circ\text{C}$ , 1 ms		96	A
<b>SSOA (RBSOA)</b>	$V_{GE} = 15\ \text{V}$ , $T_{VJ} = 125^\circ\text{C}$ , $R_G = 22\ \Omega$ Clamped inductive load, $L = 100\ \mu\text{H}$		$I_{CM} = 48$ @ $0.8\ V_{CES}$	A
$P_C$	$T_C = 25^\circ\text{C}$		150	W
$T_J$		-55 ... +150		$^\circ\text{C}$
$T_{JM}$			150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150		$^\circ\text{C}$
Maximum Lead and Tab temperature for soldering 1.6 mm (0.062 in.) from case for 10 s			300	$^\circ\text{C}$
$M_d$	Mounting torque		1.13/10	Nm/lb.in.
<b>Weight</b>			6	g

### Features

- International standard packages JEDEC TO-247 SMD surface mountable and JEDEC TO-247 AD
- High frequency IGBT and antiparallel FRED in one package
- High current handling capability
- 3rd generation HDMOS™ process
- MOS Gate turn-on - drive simplicity

### Applications

- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies

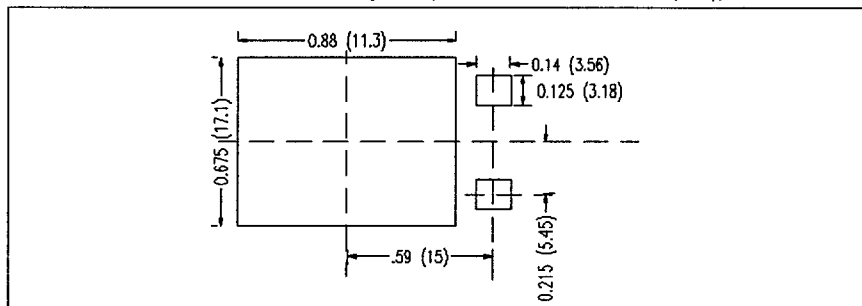
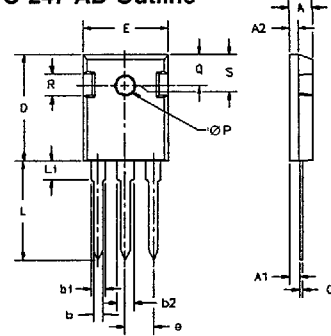
### Advantages

- Space savings (two devices in one package)
- High power density
- Suitable for surface mounting
- Switching speed for high frequency applications
- Easy to mount with 1 screw (insulated mounting screw hole)

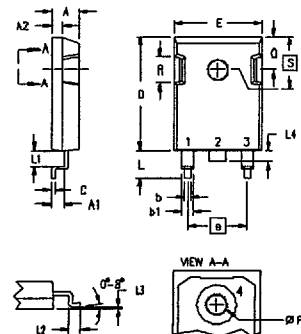
Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		min.	typ.	max.
$BV_{CES}$	$I_C = 750\ \mu\text{A}$ , $V_{GE} = 0\ \text{V}$	24N50 24N60	500 600	V V
$V_{GE(th)}$	$I_C = 250\ \mu\text{A}$ , $V_{CE} = V_{GE}$		2.5	5.5 V
$I_{CES}$	$V_{CE} = 0.8 \cdot V_{CES}$ $V_{GE} = 0\ \text{V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		500 $\mu\text{A}$ 8 mA
$I_{GES}$	$V_{CE} = 0\ \text{V}$ , $V_{GE} = \pm 20\ \text{V}$			$\pm 100\ \text{nA}$
$V_{CE(sat)}$	$I_C = I_{C90}$ , $V_{GE} = 15\ \text{V}$	24N50		2.3 V
$V_{CE(sat)}$	$I_C = I_{C90}$ , $V_{GE} = 15\ \text{V}$	24N60		2.5 V

Symbol	Test Conditions	Characteristic Values			
		$(T_J = 25^\circ\text{C}, \text{ unless otherwise specified})$			
		min.	typ.	max.	
$g_{fs}$	$I_C = I_{C90}, V_{CE} = 10\text{ V}$ Pulse test, $t \leq 300\ \mu\text{s}$ , duty cycle $\leq 2\%$	9	13	S	
$C_{ies}$	$V_{CE} = 25\text{ V}, V_{GE} = 0\text{ V}, f = 1\text{ MHz}$		1500	pF	
$C_{oes}$			175	pF	
$C_{res}$			40	pF	
$Q_g$	$I_C = I_{C90}, V_{GE} = 15\text{ V}, V_{CE} = 0.5 V_{CES}$		90	120 nC	
$Q_{ge}$			11	15 nC	
$Q_{gc}$				30 40 nC	
$t_{d(on)}$	<b>Inductive load, <math>T_J = 25^\circ\text{C}</math></b> $I_C = I_{C90}, V_{GE} = 15\text{ V}, L = 100\ \mu\text{H}$ $V_{CE} = 0.8 V_{CES}, R_G = R_{off} = 10\ \Omega$ Remarks: Switching times may increase for $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$ , higher $T_J$ or increased $R_G$		25	ns	
$t_{ri}$			15	ns	
$E_{on}$			0.6	mJ	
$t_{d(off)}$			150	200 ns	
$t_{fi}$			80	150 ns	
$E_{off}$			0.62	mJ	
			24N50BU1	0.8	mJ
			24N60BU1		
$t_{d(on)}$	<b>Inductive load, <math>T_J = 125^\circ\text{C}</math></b> $I_C = I_{C90}, V_{GE} = 15\text{ V}, L = 100\ \mu\text{H}$ $V_{CE} = 0.8 V_{CES}, R_G = R_{off} = 10\ \Omega$ Remarks: Switching times may increase for $V_{CE}(\text{Clamp}) > 0.8 \cdot V_{CES}$ , higher $T_J$ or increased $R_G$		25	ns	
$t_{ri}$			15	ns	
$E_{on}$			0.8	mJ	
$t_{d(off)}$			250	ns	
$t_{fi}$			100	ns	
$E_{off}$			0.9	mJ	
			24N50BU1	1.4	mJ
			24N60BU1		
$R_{thJC}$				0.83 K/W	
$R_{thCK}$		0.25		K/W	

Symbol	Test Conditions	Characteristic Values		
		$(T_J = 25^\circ\text{C}, \text{ unless otherwise specified})$		
		min.	typ.	max.
$V_F$	$I_F = I_{C90}, V_{GE} = 0\text{ V}$ Pulse test, $t \leq 300\ \mu\text{s}$ , duty cycle $d \leq 2\%$			1.6 V
$I_{RM}$	$I_F = I_{C90}, V_{GE} = 0\text{ V}, -di_F/dt = 240\text{ A}/\mu\text{s}$ $V_R = 360\text{ V}$ $I_F = 1\text{ A}; -di/dt = 100\text{ A}/\mu\text{s}; V_R = 30\text{ V}$		10	15 A
$t_{rr}$			150	ns
			35	50 ns
$R_{thJC}$				1 K/W

**Min. Recommended Footprint** (Dimensions in inches and (mm))

**TO-247 AD Outline**


Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.7	5.3	.185	.209
A <sub>1</sub>	2.2	2.54	.087	.102
A <sub>2</sub>	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b <sub>1</sub>	1.65	2.13	.065	.084
b <sub>2</sub>	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L <sub>1</sub>		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	.242	BSC

**TO-247 SMD Outline**


- Gate
- Collector
- Emitter
- Collector

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	.190	.205
A <sub>1</sub>	2.29	2.54	.090	.100
A <sub>2</sub>	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b <sub>1</sub>	1.91	2.13	.075	.084
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45	BSC	.215	BSC
L	4.90	5.10	.193	.201
L <sub>1</sub>	2.70	2.90	.106	.114
L <sub>2</sub>	2.10	2.30	.083	.091
L <sub>3</sub>	0.00	0.10	.00	.004
L <sub>4</sub>	1.90	2.10	.075	.083
ØP	3.55	3.65	.140	.144
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190
S	6.15	BSC	.242	BSC

IXYS reserves the right to change limits, test conditions, and dimensions.

 IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715  
 4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025

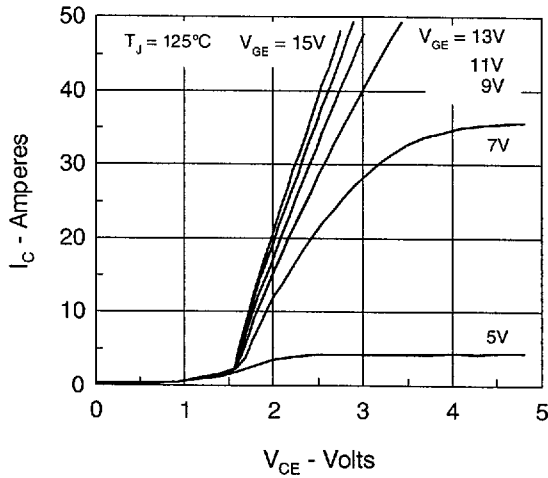


Fig. 1. Saturation Voltage Characteristics

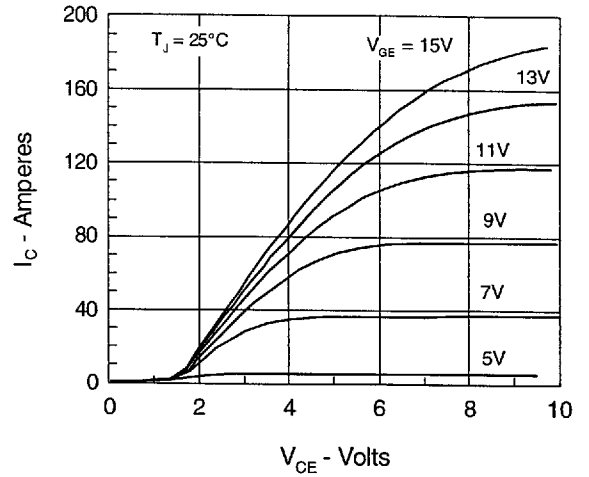


Fig. 2. Extended Output Characteristics

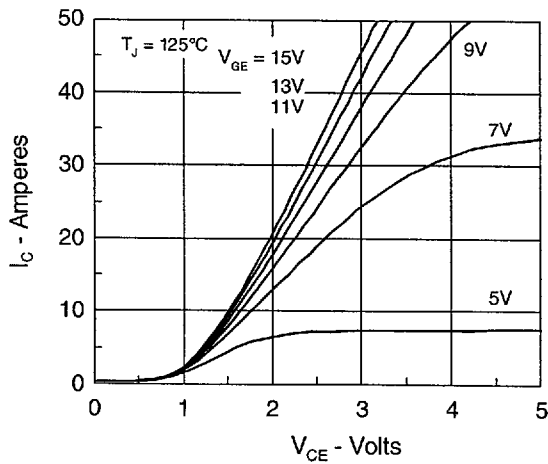


Fig. 3. Saturation Voltage Characteristics

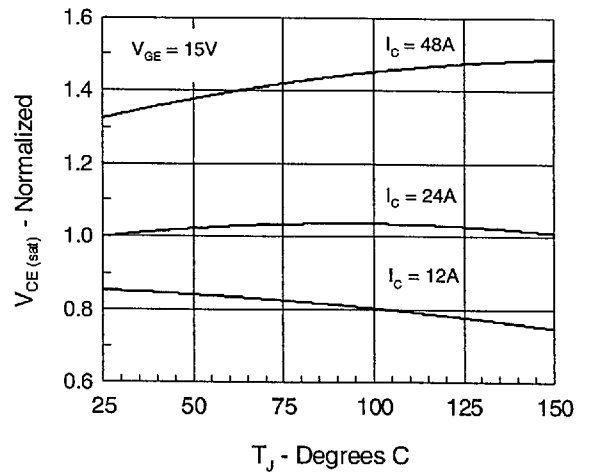


Fig. 4. Temperature Dependence of  $V_{CE(sat)}$

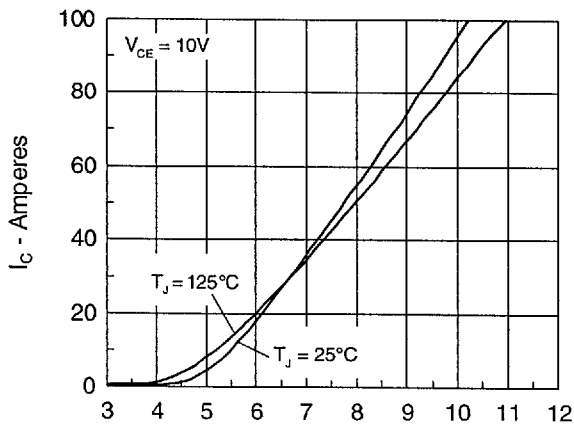


Fig. 5. Admittance Curves

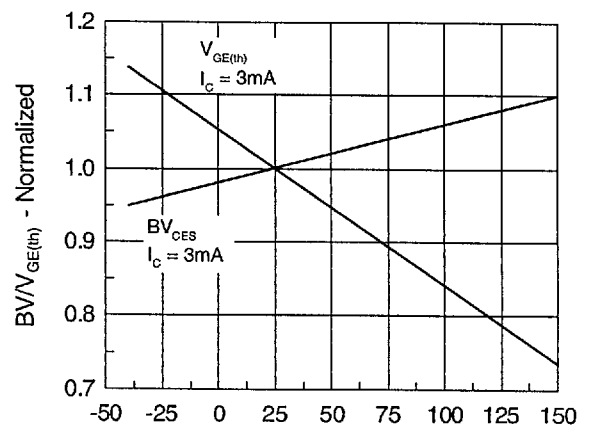


Fig. 6. Temperature Dependence of  $BV_{DSS}$  &  $V_{GE(th)}$

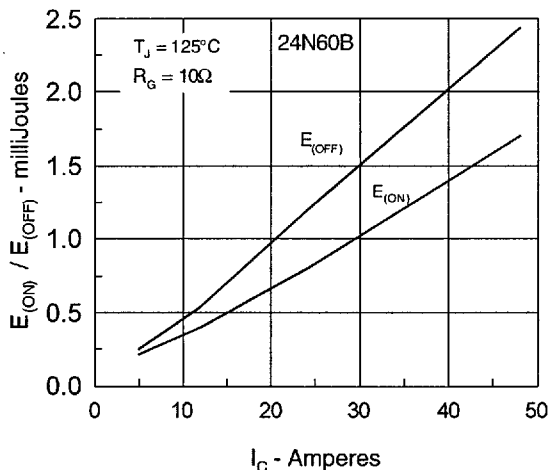


Fig. 7. Dependence of t<sub>fi</sub> and E<sub>OFF</sub> on I<sub>C</sub>.

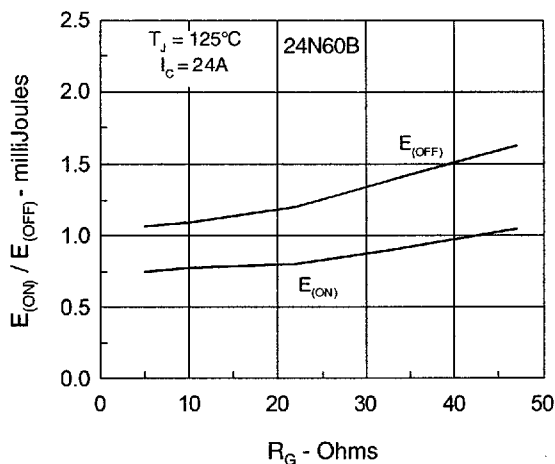


Fig. 8. Dependence of t<sub>fi</sub> and E<sub>OFF</sub> on R<sub>G</sub>.

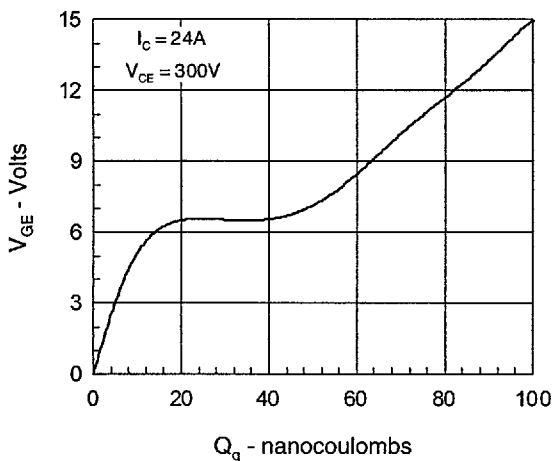


Fig. 9. Gate Charge

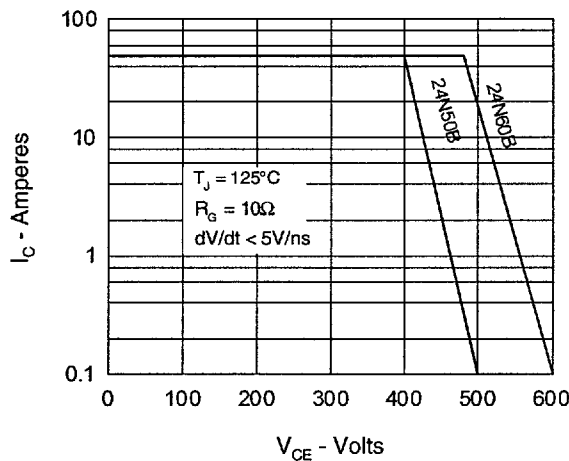


Fig. 10. Turn-off Safe Operating Area

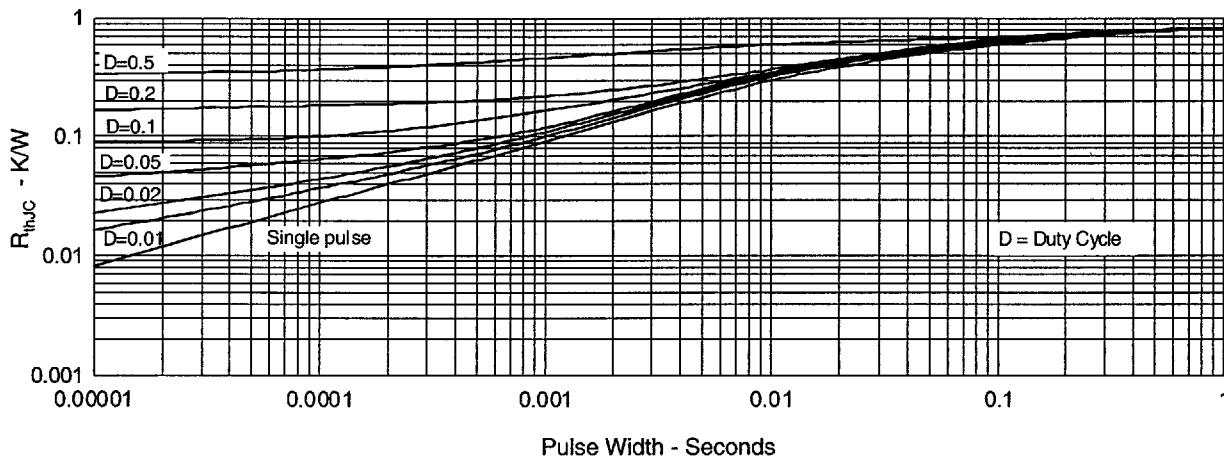


Fig. 11. Transient Thermal Resistance

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4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025

Fig.12 Maximum Forward Voltage Drop

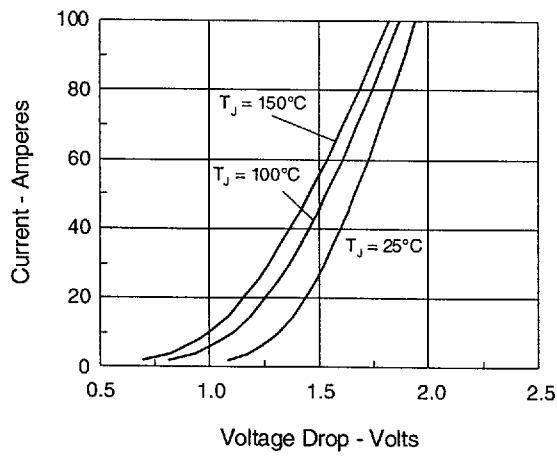
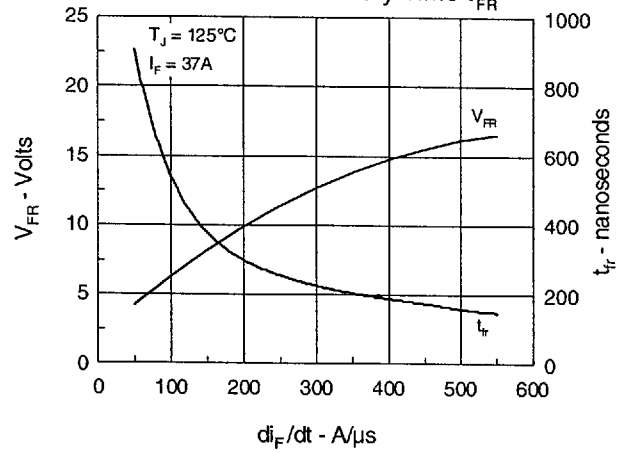
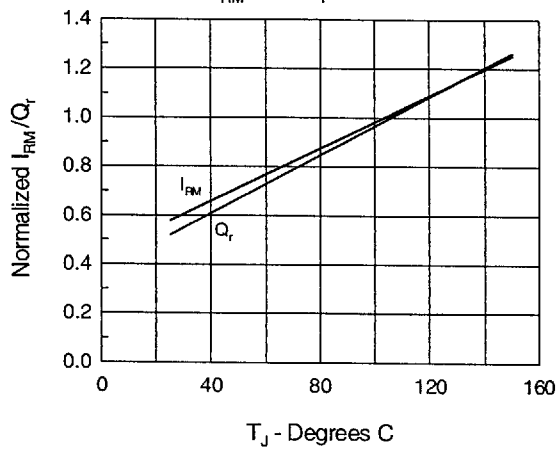

 Fig.13 Peak Forward Voltage  $V_{FR}$  and Forward Recovery Time  $t_{FR}$ 

 Fig.14 Junction Temperature Dependence off  $I_{RM}$  and  $Q_r$ 


Fig.15 Reverse Recovery Charge

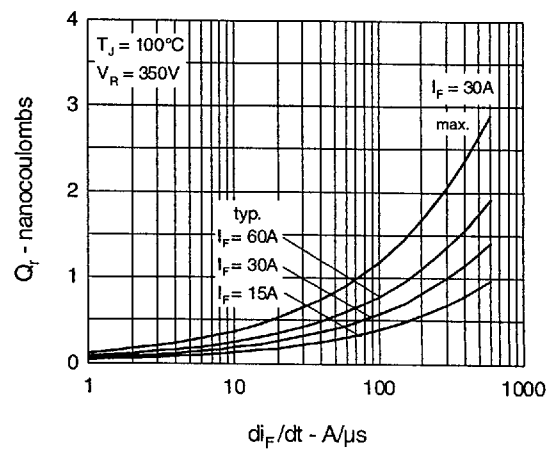


Fig.16 Peak Reverse Recovery Current

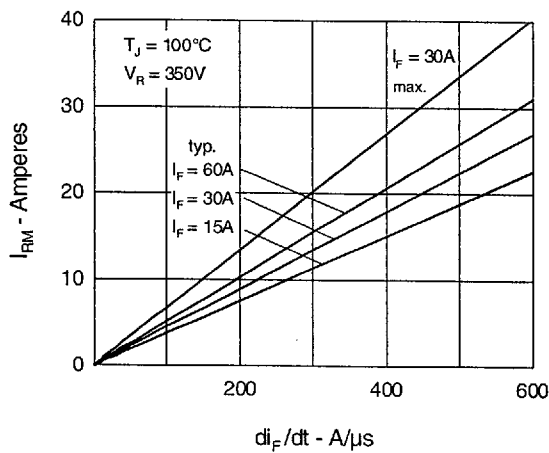


Fig.17 Reverse Recovery Time

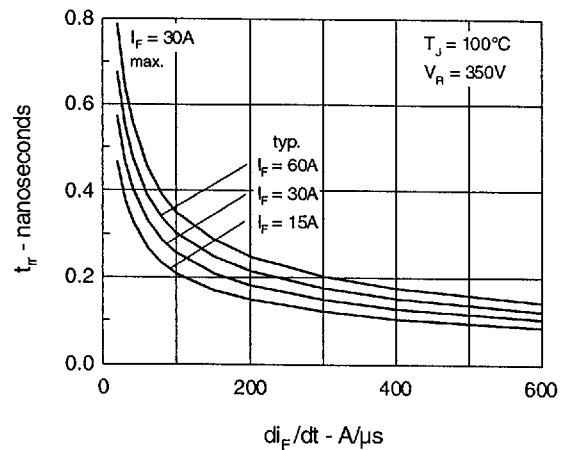
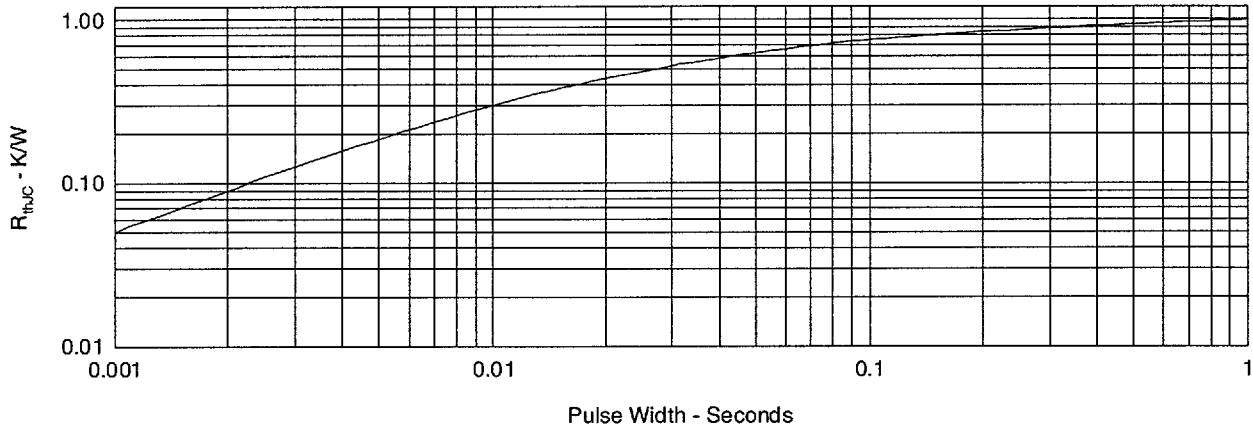


Fig.17 Diode Transient Thermal resistance junction to case



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